

	Short CV	Photo
<i>Arnaud Delcorte</i>		
<i>Andreas Wucher</i>	<p>Andreas Wucher graduated in 1981 from the Technical University Clausthal in Germany, where he earned his diploma degree in physics. He then moved to the University of Kaiserslautern and obtained his doctorate degree (Dr. rer. nat) in 1986 with fundamental research regarding the ion-induced desorption ("sputtering") of atoms and molecules from solid surfaces. He afterwards spent six months in an industrial company manufacturing surface analytical equipment, before he moved to the US and spent a post-doc year at the IBM T.J. Watson Research lab in Yorktown Heights, NY, where he worked on methods for mass spectrometric chemical surface analysis using sputtered neutral particles. After his return to Germany in 1988, he established an independent research group at the University of Kaiserslautern, where he obtained his habilitation in 1994. Since 1998, he holds a position as a Professor of Experimental Physics at the University of Duisburg-Essen.</p> <p>His scientific work concentrates on fundamental research of ion-surface interaction processes with particular emphasis on the sputtering process and its application in different technological areas. One of the main topics that has continued to be in the focus of his research concerns the ionization process as a fundamental basis for the well-known and widely-used Secondary Ion Mass Spectrometry technique.</p>	
<i>Anna Belu</i>	<p>Anna Belu is a Senior Principal Scientist, Technical Fellow and Bakken Fellow at Medtronic plc in Corporate Science and Technology. Anna has over 25 years of experience in surface science, materials, and characterization, with a keen focus on medical devices and the biointerface for the past 20 years. At Medtronic, Anna leads the Microscopy and Surface Analysis team and is Chair of the Analytical Lab Council. Anna is a Fellow of the AVS and is currently serving as Trustee. She is a member of the Scientific Committee for the International Conference on Secondary Ion Mass Spectrometry (SIMS) and is Chair of the conference in 2021.</p>	
<i>Charles W. Magee</i>	<p>Dr. Magee first started doing SIMS depth profiling in 1973 while a Member of the Technical Staff in the Materials Characterization Research Group of RCA Laboratories in Princeton, New Jersey. There he earned two RCA Outstanding Achievement Awards for his development of SIMS and its uses in semiconductor characterization. A paper published in 1979 earned him Young Author of the Year from the Electrochemical Society. He was the third recipient of the Peter Mark Memorial Award from the American Vacuum Society in 1982 and is a Fellow of the Society.</p> <p>In 1987 he co-founded Evans East; a partnership with Charles Evans and Associates. In 2005 he sold the company to form the Evans Analytical Group which was purchased in 2017 by Eurofins. He presently serves in the position of Chief Scientist of Eurofins EAG Materials Science. He has published over 200 journal articles and given over 100 invited lectures world-wide.</p>	
<i>Daniel J. Graham</i>	<p>Dan Graham PhD is a senior research scientist in Bioengineering at the University of Washington and the NESAC/BIO research coordinator. Dan's research interests include development of software tools and methods for processing of ToF-SIMS data (both spectra and images), as well as ToF-SIMS 2D and 3D imaging of cells, tissues, tissue scaffolds and other complex materials and systems. Dan is the author of the NBToolbox for advanced processing of mass spectrometry data (https://www.nb.uw.edu/mvsa/nbtoolbox).</p> <p>When not in the lab Dan enjoys photography, computer graphics and animation, mountain biking and running really long distances.</p>	